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Journal of the European Ceramic Society 27 (2007) 4265-4268

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EXAFS investigation on Sb incorporation effects to electrical transport in SnO₂ thin films deposited by sol–gel

V. Geraldo a,b, V. Briois c, L.V.A. Scalvi a,*, C.V. Santilli d

- ^a Dep. Física FC, U. Estadual Paulista UNESP, C.P. 473, 17033-360 Bauru, SP, Brazil
- ^b Instituto de Física de São Carlos-USP, C.P. 369, 13560-970 São Carlos, SP, Brazil
- ^c Synchrotron SOLEIL, L'Orme des Merisiers, BP48, 91192 Gif-sur-Yvette, France
- ^d I. Química, U. Estadual Paulista UNESP, C.P. 355, 14801-907 Araraquara, SP, Brazil

Available online 21 March 2007

Abstract

The effect of Sb doping in SnO_2 thin films prepared by the sol-gel dip-coating (SGDC) process is investigated. Electronic and structural properties are evaluated through synchrotron radiation measurements by EXAFS and XANES. These data indicate that antimony is in the oxidation state Sb^{5+} and replaces tin atoms (Sn^{4+}), at a grain surface site. Although the substitution yields net free carrier concentration, the electrical conductivity is increased only slightly, because it is reduced by the high grain boundary scattering. The overall picture leads to a shortening of the grain boundary potential, where oxygen vacancies compensate for oxygen adsorbed species, decreasing the trapped charge at grain boundary. © 2007 Elsevier Ltd. All rights reserved.

Keywords: EXAFS; Tin dioxide films; Sol-gel

1. Introduction

In the undoped form, tin dioxide (SnO₂) is a wide bandgap n-type semiconductor, due to oxygen vacancies and interstitial tin atoms. When deposited as thin films, this material is characterized by high optical transmission in the ultraviolet (UV)-visible range and good electrical conductivity, being widely used as transparent electrodes in electronic devices. ¹ SnO₂ thin film, deposited via sol-gel, is a polycrystalline combination of nanograins and the electrical properties may be controlled by the introduction of doping such as Sb5+ and the monitoring for oxygen adsorbed species on the surface and grain boundary.² Although doping with Sb⁵⁺ is an efficient process, this procedure is limited by the saturation, which takes place about 10 at% of Sb.³ Besides, antimony presents variation of its oxidation state in the SnO₂ matrix (Sb⁵⁺ and/or Sb³⁺), which may affect directly the electrical conductivity. If Sb5+ ions replace Sn⁴⁺ ions in a substitutional solid solution, they are supposed to act as donors in the SnO₂ matrix.

In this communication, SnO₂:Sb colloidal suspensions prepared by sol-gel route were used for thin film deposition by

dip-coating technique. The variation of structural properties has been investigated by using synchrotron radiation, through XANES (X-ray absorption near edge structure) and EXAFS (extended X-ray absorption fine structure) measurements, in order to obtain information on Sb oxidation state as well as the effect of Sb doping in electrical transport properties of transparent SnO_2 films.

2. Experimental

Colloidal suspensions of Sb-doped SnO_2 have been prepared with an aqueous solution of Sn^{4+} (0.5 mol/l) obtained by dissolution of $SnCl_4 \cdot 5H_2O$, and an alcoholic solution of Sb obtained by dissolution of SbF₃. The nominal concentration of solutions range from 3.0 to 16.0 at% of Sb. Hydrolysis of Sn^{4+} and Sb^{3+} ions were promoted by addition of ammonium hydroxide (NH₄OH) under stirring with a magnetic bar until pH reaches 11. The suspension was submitted to dialyses against distilled water for elimination of chloride and fluoride ions. Films were deposited by dip-coating with 10 cm/min withdrawal rate, followed by drying in air by 20 min, and placed in a muffle at 200 °C by 30 min between each of the 10 layers. Then, samples were fired at 550 °C by 1 h.

XANES and EXAFS measurements were carried out at room temperature, at HASYLAB (HAmburg SYnchrotron radiation

^{*} Corresponding author. Tel.: +55 14 3103 6084; fax: +55 14 3103 6094. E-mail address: scalvi@fc.unesp.br (L.V.A. Scalvi).

LABoratory) (4.5 GeV, 140 mA) Germany. XANES measurements at Sb L₁ edge (4698 eV) were carried out on the E4 station, using as monochromator a Si (111) double crystal. The XANES data for films were recorded in total electron yield detection mode using the detector developed by Tourillon et al.⁴ XANES spectra were normalized far from the edge (\sim 4750 eV) and analyzed in comparison to Sb₂O₃ and FeSbO₄ references to determine the Sb oxidation in the Sb-doped SnO₂ thin films. EXAFS data were recorded at Sb K edge (30491 eV) and Sn K edge (29200 eV) of ROMO II station at HASYLAB, equipped with a Si (3 1 1) double crystal monochromator which was set to 60% in order to eliminate higher harmonics. Sn K edge data were recorded in transmission mode over 1200 eV with 2 eV energy steps. Sb K edge EXAFS spectra were measured in fluorescence mode using a solid state Ge monoelement detector over 1000 eV with 2 eV energy steps. Sn K edge EXAFS oscillations were analysed according to the procedure fully described elsewhere⁵ using the EXAFS98 and ROUND Midnight programs⁶.

For electrical measurements, In electrodes have been evaporated on the samples by an Edwards evaporator system and annealed to $150\,^{\circ}\text{C}$ by $20\,\text{min}$. Low temperature data were obtained in an Air Product Cryostat that controls temperature in the range $25\text{--}300\,\text{K}$ within $0.05\,\text{K}$ of precision.

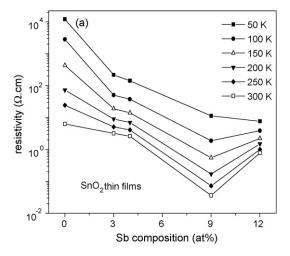
3. Results-discussion

Fig. 1(a) shows a plot of electrical resistivity as function of Sb doping for several temperatures of SnO_2 thin films. The overall effect of doping is to decrease the resistivity as the concentration of Sb doping increases until the saturation is reached, which is about 10%. Therefore, the sample with 9 at% of Sb presents the overall lower resistivity. However this resistivity is still high in comparison to films deposited by similar procedures. ^{1,7} These data raises several possibilities: (i) the doping is not being completely incorporated into the sample, (ii) the Sb doping is preferentially in the Sb³⁺ state, instead of Sb⁵⁺ (donor), giving birth to a high charge compensation and (iii) these films present a very low electron mobility.

 L_1 Sb XANES data for Sb-doped films are compared in Fig. 1(b) with XANES data for reference compounds. In the Sb₂O₃ and the FeSbO₄ compounds, the antimony presents Sb³⁺ and Sb⁵⁺ oxidation sates, respectively. The spectra present maxima at 4703 and 4707 eV for Sb₂O₃ and FeSbO₄, respectively. Then the peak about 4707 eV, observed for Sb-doped film indicates an oxidation state of Sb⁵⁺.

XANES data obtained for thin films evidence the donor nature of Sb^{5+} , which rules out hypothesis (ii). Results of reflection in the near infrared show that Drude's theory applies, which means a carrier concentration is as high as $10^{20}\,\mathrm{cm}^{-3}$. It assures that there is enough free electrons to lead to a highly degenerate semiconductor. All of these data lead us to investigate hypothesis (iii) carefully.

The influence of adding antimony to SnO_2 matrix was investigated by EXAFS at Sn K edge. The first peak (1 < R < 2.2 Å) of Fourier transform of EXAFS shown in Fig. 2(a) is related to the first oxygen coordination shell around tin atoms (Sn–O) and the second peak is related to Sn–Sn (3.19 Å), Sn–Sn (3.72 Å) and



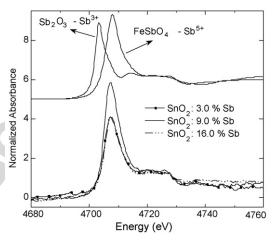


Fig. 1. (a) Resistivity as function of Sb doping in SnO₂ thin films, measured at several temperatures (lines are drawn only as a guide to the eyes). (b) XANES data for references compounds and Sb-doped SnO₂ thin films. Sb₂O₃ presents oxidation state Sb³⁺ and FeSbO₄, oxidation state Sb⁵⁺.

Sn–O (3.58 Å) contributions of the second tin nearest neighbor. The decrease of the second peak for the films compared to the crystalline SnO₂ powdered reference is due to the nanometer scale of crystallites in the films. The smaller the crystallite, the fewer neighbors are present at the second coordination shell (Sn-Sn), and, thus, the second peak in the Fourier transform (FT) of EXAFS signal is lower. It can be noticed in Fig. 2(a) that the increase of antimony concentration does not change the intensity of the first oxygen contribution indicating that the first coordination shell of oxygen remains essentially invariant upon doping. Small differences in intensity can be observed in Fig. 2(a) for the second peak, in particular higher intensities are observed for the second maximum of this peak when Sb is added. This change can be related either to an increase of the crystallite size and/or to a decrease of the disorder inside the crystallite. In the latter case, it should be observed a decrease of the Debye-Waller factor.

Table 1 presents structural parameters obtained by a least-squares fitting procedure to simulate the first two peaks of the FT displayed in Fig. 2(a). It is clearly seen that the increase in the antimony concentration does not change the number of oxygen

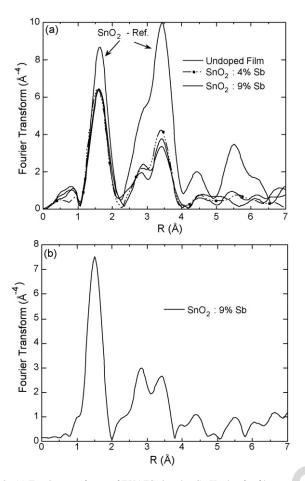


Fig. 2. (a) Fourier transforms of EXAFS signal at Sn K edge for films prepared with different Sb loadings compared to a crystalline SnO_2 reference. (b) Fourier transform of EXAFS signal at Sb K edge for SnO_2 :9%Sb thin film.

of the first coordination shell of Sn. The overall effect of addition of antimony is an increase of the coordination numbers for the tin second neighbors located at 3.73 Å, the Debye–Waller factors for the tin contributions being essentially identical. This indicates that the addition of Sb gives rise to a small increase of the size of the SnO₂ crystallite. The error bar on the size estimated for larger crystallites from coordination numbers determined by EXAFS increases with the size of the crystallite, which means particle size is estimated as 5 ± 2 nm.

Fourier transform of EXAFS signal at Sb K edge for a 9%Sb-doped SnO₂ thin film is presented in Fig. 2(b). The very similar shape of FT obtained at both K edges for the same film suggests that Sb doping ions enter into the lattice substitutional to Sn atoms. Data fitting of Sb K edge EXAFS data for SnO₂:9%Sb can be summarized as follows: number of first oxygen neighbors: 5.0 ± 0.5 , degree of disorder of the system (Debye–Waller factor): 0.09 ± 0.02 Å, distance between Sb–O atoms: 2.02 ± 0.02 Å. It is noteworthy that the Sb-O distance in first coordination shell of doping is about 2% shorter than the Sn–O distance in the SnO₂ structure.

Using the procedure already used and described for Cudoped xerogels¹⁰, we have calculated by FeFF7 the theoretical EXAFS spectra of different possible substitutional sites for antimony in SnO₂ lattice taking into account the structural contraction of 3% for the first oxygen coordination shell around Sb. No contraction of distances has been considered for Sn and O atoms located at larger distances and the same Debye–Waller factor for all the paths involved in the considered cluster, equal to 0.07 Å, has been set. Fig. 3 compares the experimental signal of SnO₂:9%Sb film with theoretical EXAFS data when antimony gets into several distinct sites, substitutional to Sn⁴⁺ ions. The best agreement between experiment and theory for the $k\chi(k)$ signal is apparently obtained for Sb located at sites g and e. ¹⁰ Nevertheless the comparison of Fourier transforms of the

Table 1
Structural parameters determined from least-square fitting of the first two peaks of the Fourier transforms of EXAFS signal at Sn K edge in Fig. 2(a)

Sample	Number of neighbors N, and type	Debye–Waller factor, σ (Å)	Interatomic distance <i>R</i> (Å)	Agreement factor ρ (%)
Crystalline	60	0.05	2.06	1.03
reference SnO ₂	2 Sn	0.04	3.21	
	8 Sn	0.05	3.74	
	4 O	0.20	3.57	
Undoped film	5.8 O	0.07	2.06	0.55
	1.7 Sn	0.06	3.21	
	5.9 Sn	0.08	3.74	
	4.00	0.18	3.65	
SnO ₂ :4%Sb	5.8 O	0.07	2.07	3.07
	1.7 Sn	0.06	3.22	
	6.5 Sn	0.08	3.75	
	4.0 O	0.12	3.63	
SnO ₂ :9%Sb	5.7 O	0.07	2.05	0.44
	1.8 Sn	0.07	3.20	
	6.3 Sn	0.08	3.72	
	4.0 O	0.16	3.59	

Accuracy in the determination is 10% for N, 20% for σ and 1% for R.

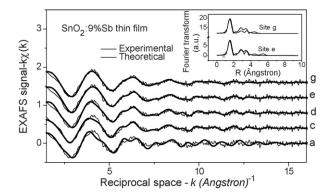


Fig. 3. (a) EXAFS signal at Sb K edge for SnO_2 :9%Sb thin film, compared to theoretical calculation (FEFF program), according to Sb position at several distinct sites. Details on sites a, c–e and g can be found in Ref. [10]. *Inset*: Fourier transform of EXAFS signal and theoretical EXAFS by sites g and e.

 $k\chi(k)$ signals for Sb impurity located at these two sites (g and e) undoubtedly addresses the site e (at cluster surface) as the best one. These results indicate that Sb enters into the lattice substitutional to Sn⁴⁺ and, moreover, the preferential site is located at grain surface. As concluded from XANES measurements (Fig. 2) the antimony presents +5 oxidation state in these films, providing the conclusion that Sb⁵⁺ substitutes Sn⁴⁺ in the SnO₂ lattice, yielding more free electrons and then, doping contribution is the improving of electrical conductivity. However, the calculation leading to Sb at an e-like site, located at the SnO₂ cluster surface, suggests also that besides substitutional position in the lattice, the impurity is also located preferentially close to grain surface. Finally it is important to stress that the substitution of Sn⁴⁺ by Sb⁵⁺ gives rise to oxygen vacancies inside the SnO₂ crystallites, which are located in the neighborhood of antimony since the average coordination of Sb is five-fold in spite of sixfold for Sn. The location of Sb close to the grain surface could explain that Sn K edge data are less sensitive to the presence of oxygen vacancies. But it appears from the Sb K edge data that Sb acts as a better probe in the SnO₂ crystallite to detect oxygen vacancy.

The picture drawn by the combination of results presented so far can be summarized as follow: highly doped SnO₂ thin films with nanoscopic grains present the doping in the Sb⁵⁺ oxidation state, which is located into the lattice substituting to Sn⁴⁺, preferentially at grain boundary layer. In addition, the Sb doping leads to an increase in the oxygen vacancy concentration, what helps to improve the free carrier concentration. Considering only the charge carriers contribution, the sample should have its resistivity substantially decreased by the high doping. However this is not observed. This picture is consistent with very low electron mobility due to grain boundary scattering associated to the nanocopic grain size. Then, the slight increase in the conductivity with doping concentration is due to oxygen vacancies surrounding Sb⁵⁺ ions, located at grain boundary layer, since it compensates for the adsorbed species and the overall result

is a decrease of the potential barrier, what increases the charge carrier mobility.

4. Conclusion

XANES data indicate that the antimony atoms are in the oxidation state +5. The *ab initio* simulation of experimental EXAFS at Sb K edge evidences the presence of antimony atoms in a substational site located at grain boundary surface region, which must influence the intergrain charge potential barrier. Besides, the increasing of Sb concentration also increases the oxygen vacancy concentration. Small grains imply in a higher amount of grains and higher grain boundary scattering, which means a very low mobility, even though the free carrier concentration is high. Film mobility is slightly increased due to Sb doping, related with lowering of grain boundary potential barrier, due to reducing trapped charge by interaction with oxygen vacancies. The general effect is to increase the film conductivity with Sb doping concentration.

Acknowledgments

The authors wish to thank Brazilian sources for financial help: CAPES, CNPq and FAPESP. DESY and the European Community is acknowledged for the financial support for the access to Hasylab (Contract RII3-CT-2004-50600, IA-SFS).

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